

12/02/2009 83:54

MOG1NNBG1EE

PAGE 83

PIPER JAFFRAY

Estimator for Form 1449A/PTO		Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT			
(use as many sheets as necessary)			
Sheet	1	of	1
		Attorney Docket Number	
		FIS820030301U81	

**Examiner
Signature** Harker T. Govee **Date
Considered** 08/25/05

*** EXAMINER: DRAFT II reference considered, whether or not citation is in conformance with MPEP 608. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to examiner.**

¹ Unique citation designation number. ² See attached kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.2). For Japanese patent documents, the indication of the year of the reign of the Emperor shall precede the serial number of the patent documents. ⁴ Kind of document by the appropriate symbol as indicated on the document under WIPO Standard ST.16 if applicable. ⁵ Applicant is to place a check mark here if English language translation is required.

/Jermele Hollington/

05/22/2006

PAGE 501 *RCVD AT 12/22/2014 2:55:16 PM (Eastern Standard Time) *SVA:USPTO-EXIF-E111 *DMS:5729306 *CSDC:4105731124 *DURATION (ms):30454

INFORMATION OF DISCLOSURE CITATION (See several boxes / sections) <i>APR 19 2005</i>			Document Number (Opposed)		Application Number		
			PIS920030301		209920-473-		
			Applicant(s)				
			Beaman, et al.				
			Filing Date	Group Art Unit			
			08/17/04	2833			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>[initials]</i>		6452406	09/17/2003	Beaman, et al.			
<i>[initials]</i>		6452408	09/17/2003	Beaman, et al.			
U.S. PATENT APPLICATION PUBLICATIONS							
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
FOREIGN PATENT DOCUMENTS							
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translates YES NO
OTHER DOCUMENTS (Including Author, Title, Date, Periodical Name, Etc.)							
JMH:	<i>LT</i>	US Application: 09/254769 Title: Wafer Scale High Density Probe Assembly, Apparatus For Use Thereof And Methods Of Fabrication Thereof Filing Date: 03/11/1999 Name: Lazro, et al.					
JMH	<i>LT</i>	US Application: 08/755481 Title: High Temperature Chip Test Probe Filing Date: 11/16/1996 Name: Lazro, et al.					
EXAMINER <i>Dawnia Hemes</i>			DATE CONSIDERED <i>08/28/05</i>				
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							